### Secondary Ion Mass Spectrometry (SIMS)
- Cameca IMS-3f with oxygen or caesium source $170.00/hour
- ION-TOF TOF-SIMS IV with Ga⁺, Cs⁺, SF₅⁺, Ar⁺, O⁺, and C₆₀⁺ beams, 8" sample stage $170.00/hour

### X-ray Photoelectron Spectroscopy (XPS)
- Kratos AXIS Ultra $170.00/hour
- Kratos AXIS Nova $170.00/hour

### Scanning Auger Microscopy (SAM)
- PHI-660 Scanning Auger Microprobe $170.00/hour

### Scanning Electron Microscopy (SEM) with Energy Dispersive X-ray (EDX) Spectroscopy
- LEO 440 SEM equipped with a Quartz XOne Light Element EDX System $150.00/hour
- Hitachi S-4500 Field Emission SEM equipped with a Quartz PCI XOne SSD X-ray Analyzer $150.00/hour
- Hitachi SU3500 Variable Pressure SEM with a Oxford AZtec X-Max50 SDD X-ray Analyzer $150.00/hour

### Atomic Force Microscopy (AFM)
- PSIA XE-100 $150.00/hour

### Surface Profilometry
- Tencor P-10 $150.00/hour

### Nanomechanical Testing
- Hysitron Ti-950 Tribometer $150.00/hour

### Laser Raman Spectroscopy
- Renishaw 2000 $170.00/hour

### Fourier Transform Infrared (FTIR) Spectroscopy
- Bruker Tensor II System with Hyperion 2000 Microscope $170.00/hour

### Optical Microscopy
- Zeiss Axioplan, Zeiss SteREO Discovery.V8, and Wild M3Z $110.00/hour

### Contact Angle Goniometry
- Ramé-Hart 100 $110.00/hour

### Microindentation Hardness Testing
- Leco LM100 $70.00/sample

### Metallographic Preparation
- Per sample $80.00/sample

### Etching
- Standard $80.00/sample
- HF or electrolytic $160.00/sample

### Priority Service (based on Monday - Friday business hours, excluding weekends and holidays)
- Five business days 25% surcharge
- Three business days 50% surcharge
- One business day 100% surcharge

### Advanced Reporting, Consulting, Data Interpretation, Post-analytical Data Processing, Sample Preparation
- Hourly basis $150.00/hour

### Travel
- Hourly basis $130.00/hour
- Car rental and fuel At cost

### Project Administration Fee
- One-time flat fee, per job $21.50

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* A minimum charge of $120.00 (including administration fee) applies to all jobs *